

## Lois Aldred

Call: 2008  
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### AREAS OF EXPERTISE

Personal Injury, International & Travel, Industrial Disease, Costs & Litigation Funding, Common Law

Lois is an experienced Personal Injury and Costs Specialist known for her approachable style, tenacious advocacy and the ability to effectively argue tricky legal points.

Lois combines her practice as a barrister with sitting as Recorder on the Midlands Circuit.

Away from Law Lois has a keen interest in travel, languages, and sustainable gardening when she isn't marshalling her trio of young sons.

She speaks (now) basic French after her time living and studying in Strasbourg, when a student along with a little Spanish and Japanese.

Before coming to the Bar Lois Taught English Language Oral Communication in Osaka, Japan.

### Fraud

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Cases involving suspected fraud form an important area of Lois' practice. She is consistently approached at an early stage to assess the merits and advise on tactics in investigating and proving suspected fundamental dishonesty. While much of her work in the area is on the instructions of Defendants, she receives Claimant instructions in high value cases where Lois' ability to provide early advice on the evidence is sought. Most recently Lois advised and acted for a major tour operator in a trial solely on the issue of fundamental dishonesty in an early-discontinued group litigation and was successful in securing a finding of fundamental dishonesty in the claims with an enforceable costs order against the Claimants pursuant to CPR 44.16(1)

### Qualifications

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LLB Law with French Law and French Language ( First Class Honours)

BVC (Very Competent)

Diplôme d'études juridiques françaises, Université Robert Schuman, Strasbourg

### Memberships & Awards

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Personal Injuries Bar Association

Oxford University Press prize for Best 1st year mark in Law French/Law German Degrees

Inner Temple Scholarship

Inner Temple Entrance Exhibition

Hubert Parry Benefactor's Scholarship

Duke of Edinburgh Entrance Exhibition